

<b>Notice of References Cited</b>	Application/Control No. 10/784,134	Applicant(s)/Patent Under Reexamination FRANKOWSKY, GERD	
	Examiner Cynthia Britt	Art Unit 2117	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-			
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**FOREIGN PATENT DOCUMENTS**

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**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Session XVIII: Test and Packageing A single Chip Functional Tester by Miyamoto et al. ISSCC 87 Feb 26, 1987
	V	Automatic In-Line Measurement for the Identification of Killer Defects by Wilson et al. Presented at ICMTS 1994
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
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